

Notice of References Cited

Application/Control No.

10/647,106

Applicant(s)/Patent Under
Reexamination
BOOKER ET AL.

Examiner

Qing Chen

Art Unit

2191

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NON-PATENT DOCUMENTS

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	X	Tikir et al., "Efficient Instrumentation for Code Coverage Testing," July 2002, ACM, pg. 86-96.				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.